Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/888,795	JIAN ET AL.	
Examiner	Art Unit	
TAN TRINH	2684	

	SEARCHED				
Class	Subclass	Date	Examiner		
455	67.13	6/1/2006	π		
	556.1				
	114.3				
	144				
	194.2				
	211				
375	396				
342	373				
327	356				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES   STRATEGY	)
	DATE	EXMR
EAST	6/1/2006	π
VO, NGUYEN	6/1/2006	тт
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